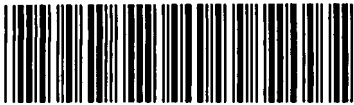


**Search Notes**

Application/Control No.

10/716,879

Examiner

Alex Liew

Applicant(s)/Patent under  
Reexamination

SCHEIER ET AL.

Art Unit

2624

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
345/163-167, 179-183 limited to text search	6/23/2007	AL
382/106, 115-118, 124-127, 154, 179-183 limited to text search	6/23/2007	AL